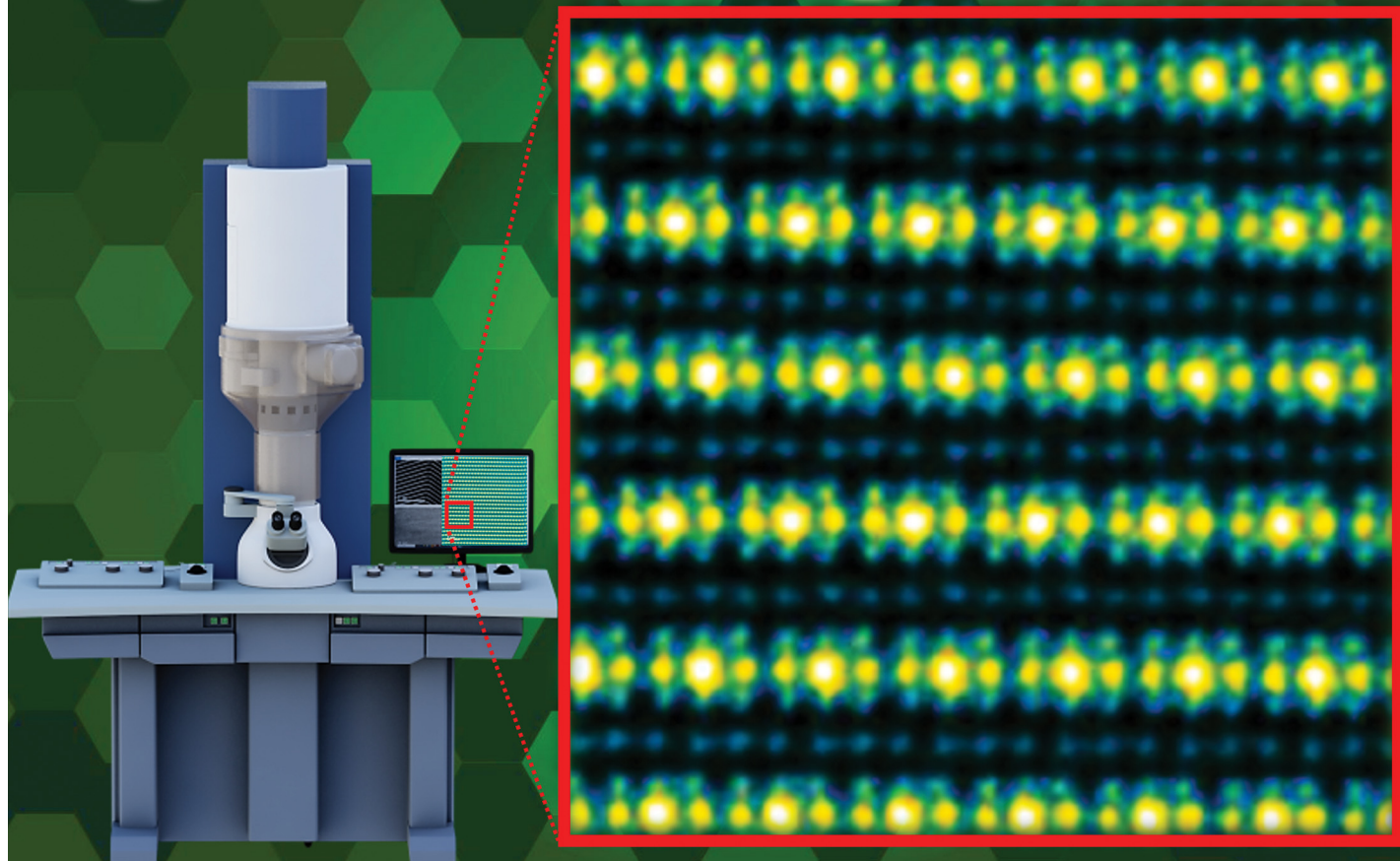


Optimum Bright-Field



Showcasing research from the National Institute of Advanced Industrial Science and Technology (AIST) and Sumika Chemical Analysis Service (SCAS), Ltd., Japan.

Probing the atomic arrangement of honeycomb layered oxides *via* optimum bright-field scanning transmission electron microscopy (OBF-STEM)

This study employs highly dose-efficient, atomic-resolution optimum bright-field scanning transmission electron microscopy (OBF-STEM), enabling the probing of atomic arrangements in honeycomb-layered oxides. The successful application of OBF-STEM facilitates the structural characterisation of electron-beam-sensitive honeycomb-layered oxide materials, thereby advancing the frontier of observation techniques for the effective investigation of emergent physicochemical phenomena.

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